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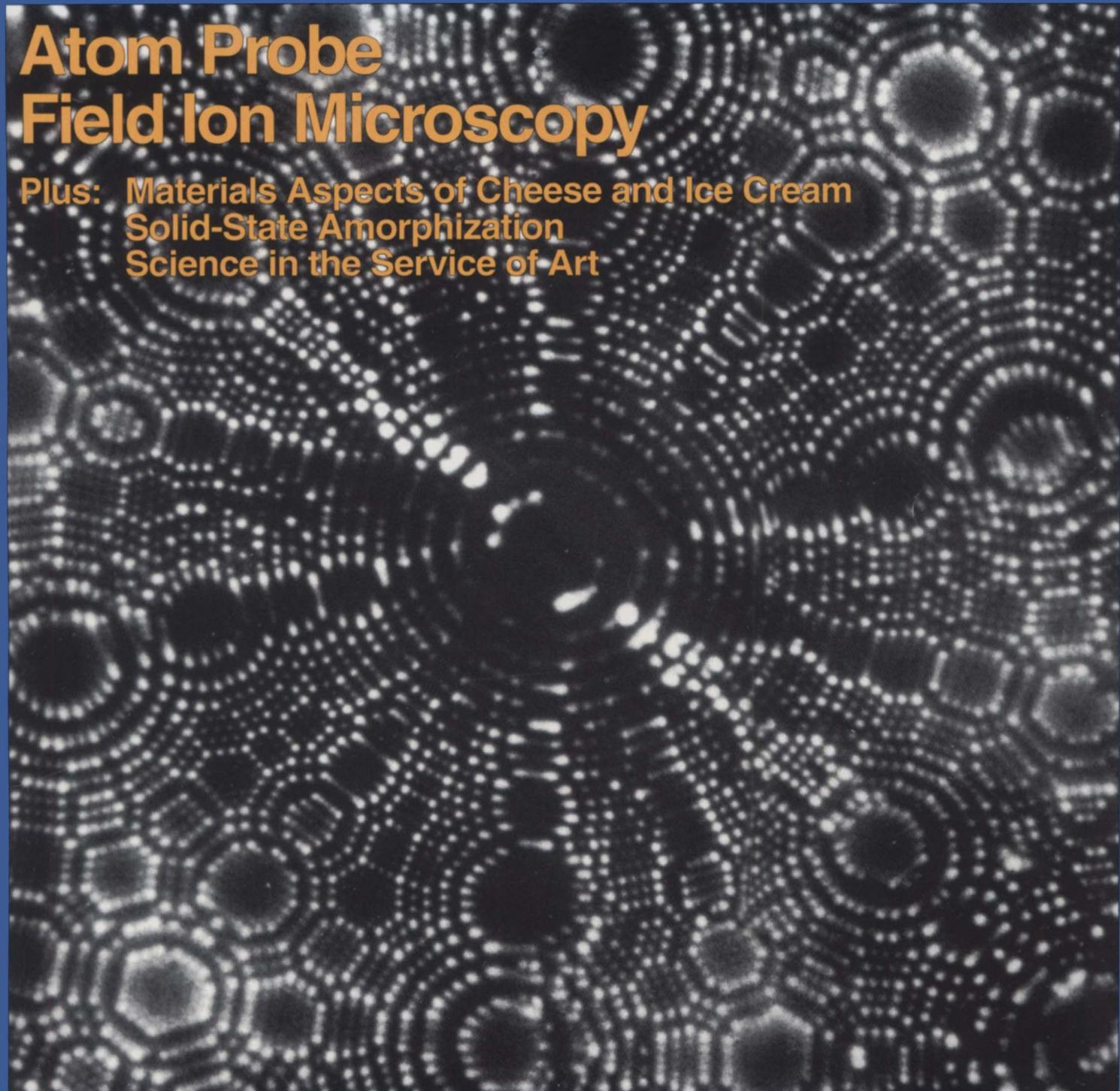
A Publication of the Materials Research Society

July 1994, Volume XIX, No. 7



Atom Probe Field Ion Microscopy

Plus: Materials Aspects of Cheese and Ice Cream
Solid-State Amorphization
Science in the Service of Art



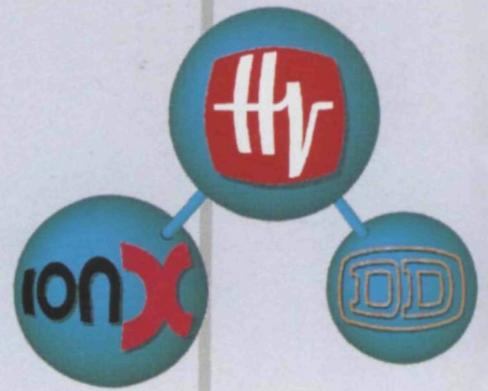
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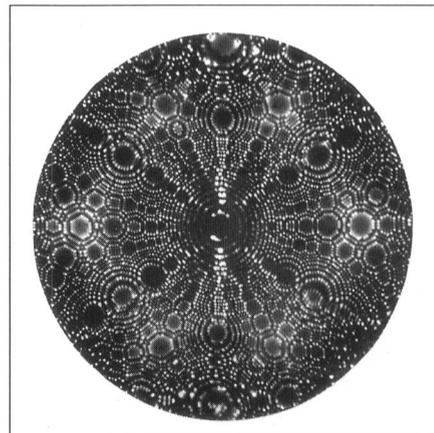
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ON THE COVER: Field ion image of a tungsten tip. Original magnification: 2,000,000X. For more about this topic, see the three technical features, p. 21-40, on atom probe field ion microscopy compiled by Tien T. Tsong, director and distinguished research fellow, Institute of Physics, Academia Sinica, Taiwan.

About the Materials Research Society

The Materials Research Society (MRS), a non-profit scientific association founded in 1973, promotes interdisciplinary goal-oriented basic research on materials of technological importance. Membership in the Society includes nearly 11,600 scientists, engineers, and research managers from industrial, government, and university research laboratories in the United States and nearly 50 countries.

The Society's interdisciplinary approach differs from that of single-discipline professional societies because it promotes information exchange across the many technical fields touching materials development. MRS sponsors two major international annual meetings encompassing approximately 50 topical symposia, and also sponsors numerous single-topic scientific meetings. The Society recognizes professional and technical excellence, conducts short courses, and fosters technical interaction in local geographic regions through Sections and University Chapters.

MRS participates in the international arena of materials research through the International Union of Materials Research Societies (IUMRS). MRS is an affiliate of the American Institute of Physics.

MRS publishes symposium proceedings, *MRS Bulletin*, *Journal of Materials Research*, and other publications related to current research activities.

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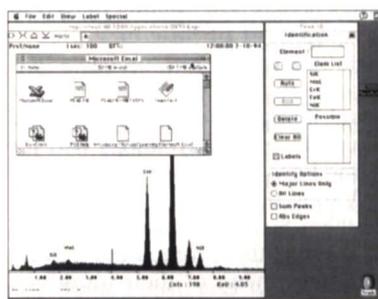
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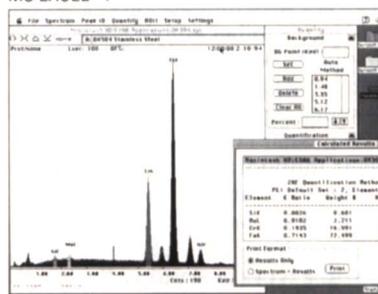
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